

; PALASM Design Description

; ----- Declaration Segment -----

TITLE 5. Versuch Teil a
 PATTERN
 REVISION
 AUTHOR ???
 COMPANY RWTH
 DATE 06/24/02

CHIP _versuch5 PALCE16V8

; ----- PIN Declarations -----

PIN 2 DA;
 PIN 3 DB;
 PIN 4 DC;
 PIN 5 DD;
 PIN 10 GND;
 PIN 12 A COMBINATORIAL ;
 PIN 13 B COMBINATORIAL ;
 PIN 14 C COMBINATORIAL ;
 PIN 15 D COMBINATORIAL ;
 PIN 16 E COMBINATORIAL ;
 PIN 17 F COMBINATORIAL ;
 PIN 18 G COMBINATORIAL ;
 PIN 20 Vcc;

; ----- Boolean Equation Segment -----

EQUATIONS
 $A = (\overline{DA} * \overline{DB} * \overline{DC} * \overline{DD}) + (\overline{DA} * \overline{DB} * DC * \overline{DD});$
 $B = (\overline{DA} * \overline{DB} * DC * \overline{DD}) + (\overline{DA} * DB * DC * \overline{DD});$
 $C = (\overline{DA} * DB * \overline{DC} * \overline{DD});$
 $D = (\overline{DA} * \overline{DB} * \overline{DC} * \overline{DD}) + (\overline{DA} * \overline{DB} * DC * \overline{DD}) + (DA * DB * DC * \overline{DD});$
 $E = (\overline{DA} * \overline{DB} * \overline{DC} * \overline{DD}) + (DA * DB * \overline{DC} * \overline{DD}) + (\overline{DA} * \overline{DB} * DC * \overline{DD}) +$
 $(\overline{DA} * \overline{DB} * DC * \overline{DD}) + (DA * DB * DC * \overline{DD}) + (DA * \overline{DB} * \overline{DC} * \overline{DD});$
 $F = (\overline{DA} * \overline{DB} * \overline{DC} * \overline{DD}) + (\overline{DA} * DB * \overline{DC} * \overline{DD}) + (DA * DB * \overline{DC} * \overline{DD}) +$
 $(DA * DB * DC * \overline{DD});$
 $G = (\overline{DA} * \overline{DB} * \overline{DC} * \overline{DD}) + (DA * \overline{DB} * \overline{DC} * \overline{DD}) + (DA * DB * DC * \overline{DD});$

; ----- Simulation Segment -----

SIMULATION
 SETF /DA /DB /DC /DD
 CHECK /A /B /C /D /E /F G
 SETF DA /DB /DC /DD
 CHECK A /B /C D E F G
 SETF /DA DB /DC /DD
 CHECK /A /B C /D /E F /G
 SETF DA DB /DC /DD
 CHECK /A /B /C /D E F /G
 SETF /DA /DB DC /DD
 CHECK A /B /C D E /F /G
 SETF DA /DB DC /DD
 CHECK /A B /C /D E /F /G
 SETF /DA DB DC /DD
 CHECK /A B /C /D /E /F /G
 SETF DA DB DC /DD
 CHECK /A /B /C D E F G
 SETF /DA /DB /DC DD
 CHECK /A /B /C /D /E /F /G
 SETF DA /DB /DC DD
 CHECK /A /B /C /D E /F /G

; PALASM Design Description

; ----- Declaration Segment -----

TITLE Veruch5 - Teil b
 PATTERN
 REVISION
 AUTHOR ???
 COMPANY RWTH
 DATE 06/24/02

CHIP _teilb PALCE16V8

; ----- PIN Declarations -----

PIN 1	clk		;
PIN 2	DA		;
PIN 3	DB		;
PIN 4	DC		;
PIN 5	DD		;
PIN 6	ENP		;
PIN 8	LOAD		;
PIN 10	GND		;
PIN 11	OE		;
PIN 12	QA	REGISTERED	;
PIN 13	QB	REGISTERED	;
PIN 14	QC	REGISTERED	;
PIN 15	QD	REGISTERED	;
PIN 16	RCO	COMBINATORIAL;	;
PIN 20	Vcc		;

; ----- Boolean Equation Segment -----

EQUATIONS

RCO = (ENP * QA * /QB * /QC * QD * LOAD);

QA = (ENP * /QA * LOAD) + (/ENP * QA * LOAD);

QB = (ENP * QA * /QB * /QC * /QD * LOAD) + (ENP * /QA * QB * /QC * /QD * LOAD)
 + (ENP * QA * /QB * QC * /QD * LOAD) + (ENP * /QA * QB * QC * /QD * LOAD)
 + (/ENP * /QA * QB * /QC * /QD * LOAD) + (/ENP * QA * QB * /QC * /QD * LOAD)
 + (/ENP * /QA * QB * QC * /QD * LOAD) + (/ENP * QA * QB * QC * /QD * LOAD);

QC = (ENP * QA * QB * /QC * /QD * LOAD) + (ENP * /QA * /QB * QC * /QD * LOAD)
 + (ENP * QA * /QB * QC * /QD * LOAD) + (ENP * /QA * QB * QC * /QD * LOAD) +
 (/ENP * /QA * /QB * QC * /QD * LOAD) + (/ENP * QA * /QB * QC * /QD * LOAD) +
 (/ENP * /QA * QB * QC * /QD * LOAD) + (/ENP * QA * QB * QC * /QD * LOAD);

QD = (ENP * QA * QB * QC * /QD * LOAD) + (ENP * /QA * /QB * /QC * QD * LOAD) +
 (/ENP * /QA * /QB * /QC * QD * LOAD) + (/ENP * QA * /QB * /QC * QD * LOAD);

; ----- Simulation Segment -----

SIMULATION

SETF /LOAD /DA /DB /DC /DD /ENP /OE

clockf clk

SETF ENP LOAD

for i:= 1 to 10 do

begin

clockf clk

end

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